

<b>Notice of References Cited</b>	Application/Control No. 10/659,762	Applicant(s)/Patent Under Reexamination WARILA ET AL.	
	Examiner Isaac T. Tecklu	Art Unit 2192	Page 1 of 1

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*	B	US-6,941,520	09-2005	Lewallen, Stephen Richard	715/762
*	C	US-6,707,475	03-2004	Snyder, Mark I.	715/771
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	M	US-			

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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